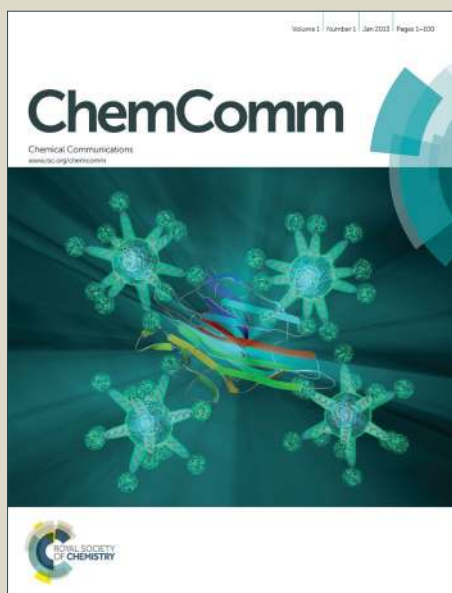


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## High Performance Ternary Nickel Cobalt Sulfide Micro-pseudocapacitor

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Received 00th January 20xx,  
Accepted 00th January 20xx

DOI: 10.1039/x0xx00000x

www.rsc.org/

**We report the successful fabrication of a micro-pseudocapacitor based on ternary nickel cobalt sulfide for the first time, with performance substantially exceeding that of previously reported micro-pseudocapacitors based on binary sulfides. CoNi<sub>2</sub>S<sub>4</sub> micro-pseudocapacitor exhibits a maximum energy density of 18.7 mWh/cm<sup>3</sup> at a power density of 1163 mW/cm<sup>3</sup>, opens up an avenue for exploring new family of ternary oxides/sulfides based micro-pseudocapacitors.**

Microsupercapacitors (MSCs) are promising devices for next generation on-chip energy storage due to their high power density, which can complement high energy density batteries.<sup>1-3</sup> Additional attributes of MSCs include excellent rate capability, long cycling lifetime, and superior volumetric capacity to their conventional sandwich counter-parts.<sup>3,4</sup> The planar configuration of MSCs can allow robust integration with functional electronic devices such as microsensors and biomedical implants as micro-power units.<sup>5-7</sup> Hence, a great deal of research has been focused on a variety of nanostructured electroactive materials that are amenable to fabricate in-plane MSCs.<sup>3,4</sup>

Various MSCs based on conducting porous carbon were fabricated employing conventional photolithography and deposition or etching schemes. For example, high surface area carbon forms such as activated,<sup>8</sup> carbide derived,<sup>2</sup> onion like<sup>9</sup> and carbon nanotubes<sup>10</sup> have been patterned employing photolithography followed by deposition methods such as ink-jet printing, electrophoretic and spray deposition. Further, high temperature chemical vapor deposition (CVD) was also employed in growing carbon nanotubes (CNTs) and graphene or both selectively over the patterned current collectors.<sup>11,12</sup> Of late, due to compatible solution processability, graphene oxide (GO) has become attractive candidate material for making MSCs employing etching scheme in a photolithography technique<sup>13</sup> or innovative direct laser scribing methods.<sup>14,15</sup> Further, in order to improve the limited capacitance of carbon based MSCs, several pseudocapacitive materials including metal oxides/hydroxides (RuO<sub>2</sub>, MnO<sub>2</sub> and Ni(OH)<sub>2</sub>),<sup>16-18</sup> and even conducting polymers (PPY, PANI, PEDOT)<sup>19-22</sup> were employed to fabricate high capacity micro-pseudocapacitors. These pseudocapacitive materials can undergo fast redox reactions at their nanostructured surfaces, contributing to the higher values of capacity and hence energy density.<sup>16-22</sup>

Recently, new electrode materials in the form of binary and ternary sulfides have been explored as potential candidates for pseudocapacitors.<sup>23-25</sup> However, most of the studies have been focused on synthesis and investigating their electrochemical performance in 3-electrode configuration. To exploit the practical usage of these new materials, it is highly desirable to build energy storage devices in a 2-electrode configuration.<sup>25,26</sup> In-plane MSCs based on binary metal sulfides such as MoS<sub>2</sub> and VS<sub>2</sub> have been fabricated which showed an areal cell capacitance of 5-8 mF/cm<sup>2</sup>.<sup>27,28</sup> Moreover, nanostructured sulfides, in particular, ternary nickel cobalt sulfides have become outstanding electrode materials due to their higher conductivity richer redox reactions than the single component sulfides due to contributions from nickel and cobalt ions.<sup>23-25</sup> In addition, it was demonstrated that these ternary cobalt nickel sulfides exhibit higher electronic conductivity and richer redox reactions than their ternary oxide counter-parts, resulting in higher capacity values.<sup>29</sup> Here, we demonstrate the fabrication of ternary sulfide micro-pseudocapacitors with excellent volumetric capacitance and energy density.

We report the fabrication of nanostructured ternary cobalt nickel sulfide micro-pseudocapacitor employing electrochemical co-deposition over the rGO/Au/patterned photoresist. The rGO free-standing films are prepared through vacuum filtration from its dispersion. Before doing lift-off, ternary cobalt nickel sulfide was electrodeposited to ensure uniform deposition over the entire area. The resulting CoNi<sub>2</sub>S<sub>4</sub> MSC exhibits a volumetric capacitance of 211 F/cm<sup>3</sup> (areal capacitance of 11.6 mF/cm<sup>2</sup>), corresponding to an energy density of 18.7 mWh/cm<sup>3</sup> at a power density of 1163 mW/cm<sup>3</sup>. This is the best reported performance of any sulfide based micro-pseudocapacitor.

Glass substrates (Fischer) were cut into 1x1" size, cleaned with a soap solution to remove the dirt or grease followed by sonicating in acetone, isopropanol and deionized water sequentially for 5 minutes each and then dried by blowing nitrogen. Positive photoresist AZ9260 was spun coated at 3000 rpm for 60 seconds over the glass substrates to get 10 μm thick photoresist layer. Photoresist coated substrates were soft baked at 110 °C for 3 minutes. Ultra-Violet (UV) exposure was done using EVG contact aligner at a constant dose of 1800 mJ/cm<sup>2</sup> through the Cr/Glass mask having the interdigitated patterns. After the exposure, samples were developed in AZ726 developer solution for 6 minutes, which resulted in the formation of patterns in the photoresist layer. Metal layers of 200 nm Au/20 nm Ti were deposited by sputtering (Equipment Support Co., Cambridge, England) technique over the patterned photoresist layer. Before the lift-off process, free-standing rGO film obtained through vacuum filtration was transferred onto metal-coated patterned photoresist followed by electrochemical co-deposition of nickel cobalt sulfide.<sup>25</sup>

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<sup>†</sup> Footnotes relating to the title and/or authors should appear here. Electronic Supplementary Information (ESI) available: [details of any supplementary information available should be included here]. See DOI: 10.1039/x0xx00000x

Graphite oxide was prepared from natural graphite source using a modified Hummers method.<sup>30</sup> Thus obtained graphite oxide was exfoliated in de-ionized (DI) water by sonicating using a bath sonicator (UP400S, Ultrasonic processor; Hielscher ultrasound Technology) for 1hr. The resulting graphene oxide was then reduced to graphene by following a method reported by Li et al.<sup>31</sup> The supernatant solution containing thin layers of graphene was used for obtaining free-standing rGO films. The rGO dispersion was filtered using vacuum filtration (VF) method on a porous alumina membrane filter (0.2  $\mu\text{m}$  pore size and 25 mm diameter; Whatman).<sup>32</sup> The alumina membrane was removed by dissolving it into a bath of 3M NaOH solution in order to obtain free-standing rGO film. This film was then transferred to a water bath to remove the traces of adsorbed NaOH over the rGO surface and this step was repeated for several times. Finally, rGO film was transferred onto the Au-coated patterned photoresist chip followed by drying off in a heating oven at 60  $^{\circ}\text{C}$  for 3 minutes.

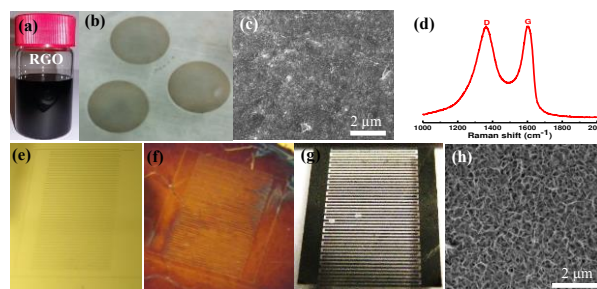
An optimized recipe reported in the reference 25 was employed for electrochemical co-deposition, consists of 5 mM  $\text{CoCl}_2 \cdot 6\text{H}_2\text{O}$  with 7.5 mM  $\text{NiCl}_2 \cdot 6\text{H}_2\text{O}$  and 0.75 M thiourea ( $\text{CS}(\text{NH}_2)_2$ ), resulting in the  $\text{CoNi}_2\text{S}_4$ . The pH value of the solution was adjusted with diluted  $\text{NH}_3 \cdot \text{H}_2\text{O}$  to  $\sim 6$ . The potentiodynamic deposition was carried out in a three-electrode cell using rGO/Au coated patterned photoresist, Pt as counter, and Ag/AgCl as reference electrodes by cyclic voltammetry at a scan rate of 5 mV/s for 1-6 cycles within a potential range of -1.2 to 0.2 V vs. Ag/AgCl.<sup>25</sup> After the electrodeposition, substrates were cleaned by rinsing with water to remove unreacted initial precursor solution, followed by drying in air and drying at 60  $^{\circ}\text{C}$  for 3 min.

Surface morphology and microstructure were imaged by scanning electron microscope (SEM) (Nova Nano 630 instrument, FEI Co., The Netherlands). The film thicknesses were measured using a Veeco Dektak 150 surface profilometer. X-ray photoelectron spectroscopy (XPS) analysis was carried out in a Kratos Axis Ultra DLD spectrometer equipped with a monochromatic Al  $K_{\alpha}$  X-ray source ( $h\nu = 1486.6$  eV) operating at 150 W, a multi-channel plate and delay line detector under a vacuum of  $\sim 10^{-9}$  mbar. The high-resolution spectra were collected at fixed analyzer pass energy of 20 eV.

The electrochemical performance of  $\text{CoNi}_2\text{S}_4/\text{rGO}$  MSCs was investigated in a 2-electrode configuration using an electrochemical workstation (CHI 660D, CH Instruments Incorporation). Cyclic voltammetry (CV), galvanostatic charge-discharge (CD), and electrochemical impedance spectroscopy (EIS) measurements were carried out in 1M KOH electrolyte. CV experiments were carried out at different scan rates selected from 0.01 to 50 V/s. CD experiments were performed using current densities selected from 60 to 320  $\mu\text{A}/\text{cm}^2$ . The electrochemical impedance spectroscopy (EIS) was measured using a Modulab (Solartron Analytical) electrochemical workstation in the frequency range from 100 kHz to 0.1 Hz at open circuit potential by applying a small sinusoidal potential of 10 mV signal. Electrochemical cycling stability was measured using VMP3 multichannel electrochemical workstation (Bio-Logic). All measurements were done at room temperature.

Figure 1a shows the rGO dispersion (described in the experimental section) that was used to obtain rGO thin films by vacuum filtration over anodic alumina membrane. The alumina membrane was subsequently dissolved away in 3M NaOH to result in the freely floating film of rGO over the water bath as shown in Fig. 1b. This rGO film is comprised of tightly packed small flakes (lateral dimensions, 200 nm) giving rise to innumerable edges, domain boundaries, and interfaces. Raman spectrum of rGO film shows broad D and G bands centered at 1367 (FWHM, 206  $\text{cm}^{-1}$ ) and 1598  $\text{cm}^{-1}$  (FWHM, 91  $\text{cm}^{-1}$ ), respectively. The D band originates from the presence of defects and functional groups while the G band corresponds to symmetric stretching of  $sp^2$  carbon lattice with  $E_{2g}$  symmetry.<sup>33</sup> The  $I_D/I_G$  ratio of rGO films was found to be in the range of 0.8-0.9 and the  $sp^2$  crystallite size was estimated using below the formula,<sup>34</sup> found to be 10-15 nm.  $E_{\text{laser}}$  is the laser excitation energy (eV) in the following equation.

$$L_a(\text{nm}) = 560/E_{\text{laser}}^4(I_D/I_G)^{-1} \dots \dots \dots (1)$$

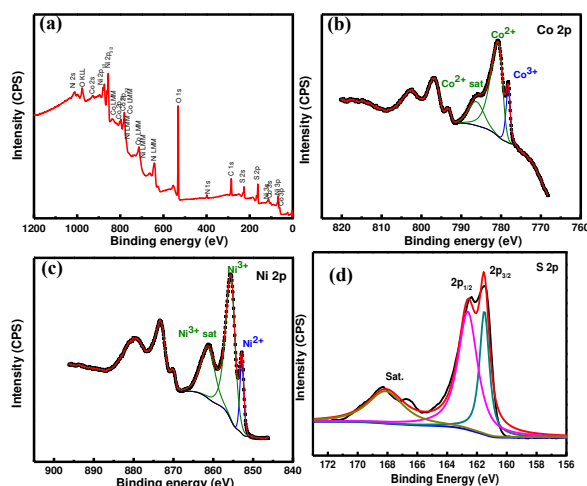


**Fig. 1** Digital photographs showing (a) rGO dispersion, (b) freely floating rGO thin film obtained through vacuum filtration. (c) SEM micrograph showing the morphology of rGO film. (d) Raman spectrum of rGO. Photographs showing (e) Au coated patterned photoresist, (f) transferring of rGO onto Au/patterned photoresist, (g) electrochemical co-deposition of  $\text{CoNi}_2\text{S}_4$  followed by lift-off in resulting  $\text{CoNi}_2\text{S}_4$  interdigitated electrodes. (h) nanostructured morphology of  $\text{CoNi}_2\text{S}_4$ .

We have followed conventional photolithography lift-off protocol to fabricate ternary nickel cobalt sulfide micro-pseudocapacitors (Detailed fabrication process is illustrated in the electronic supplementary information, Fig. S1). Initially, metal coated patterned photoresist chip was employed as a platform to transfer free-standing rGO film as shown in Fig. 1e and 1f. Reduced graphene oxide (rGO) provides a functional conductive graphitic platform which, when used as current collector, improves the nucleation and growth of pseudocapacitive materials compared to metal current collectors.<sup>35</sup> Recently, Du et al. have demonstrated a physical approach in synthesizing nanocomposite of  $\text{CoNi}_2\text{S}_4/\text{graphene}$  with excellent electrochemical performance.<sup>36</sup> We have found that compared to the metal surfaces such as Au or Ni, functional rGO surface helps in the uniform growth of ternary sulfides (Fig. S2, ESI). It was observed that the growth of  $\text{CoNi}_2\text{S}_4$  was non-uniform over the Au current collectors as evident from the SEM micrographs shown in Fig. S2. However, Au acts as a conductive support/current collector while rGO layer helps in the homogenous and uniform nucleation and growth of  $\text{CoNi}_2\text{S}_4$  during electrochemical co-deposition process. Electrochemical co-deposition was carried out before doing the photoresist lift-off to ensure uniform electric field and uniform growth of  $\text{CoNi}_2\text{S}_4$  over the entire chip. Doing the resist lift-off before electrodeposition would have created irregular electric fields and non-uniform growth of the  $\text{CoNi}_2\text{S}_4$ . The strong adherence of nickel cobalt sulfide onto the rGO film is evident since the final step of lift-off involved rigorous ultrasonication to make the  $\text{CoNi}_2\text{S}_4/\text{rGO}$  finger electrodes. It is obvious from the SEM micrograph shown in the Fig. 1h the electrodeposited  $\text{CoNi}_2\text{S}_4$  layer has a uniform monolithic morphology. We have considered rGO thin film as a platform for growing  $\text{CoNi}_2\text{S}_4$  heterostructures with interdigitated electrode patterns in evaluating its electrochemical performance in a 2-electrode configuration.

XPS analysis was carried out in order to determine the chemical composition of the sample and the oxidation state of detected elements. High resolution XPS spectra of Co 2p, Ni 2p, and S 2p core levels have been recorded and are shown in Fig. 2. The high resolution XPS spectra match well with those obtained for ternary nickel cobalt sulfides  $\text{CoNi}_2\text{S}_4$ <sup>37</sup> and  $\text{NiCo}_2\text{S}_4$ .<sup>38,39</sup> Precise distinction between the two sulfides is difficult due to the similarities of the shape and binding energies of the Co 2p, Ni 2p and S 2p core levels. The elemental composition was obtained using XPS by applying the appropriate relative sensitivity factors (RSFs) to the integrated peak areas of specific core levels for the different elements. The atomic ratio S/Ni/Co was estimated to be 4:2:1, which can be assigned to  $\text{CoNi}_2\text{S}_4$ . The Ni 2p<sub>3/2</sub> portion of the Ni 2p spectrum was fitted using three components.

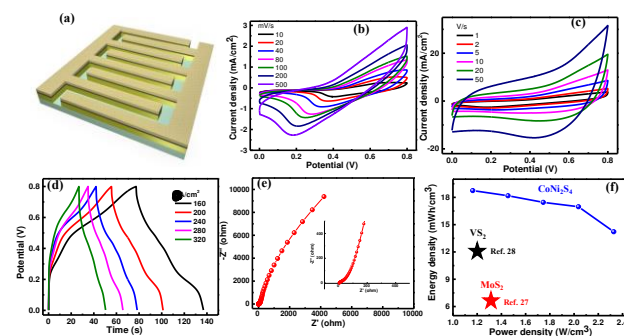
The Ni  $2p_{3/2}$  components observed at 852.9 and 855.7 eV correspond to  $Ni^{2+}$  and  $Ni^{3+}$  species, respectively.<sup>37,40</sup> The third Ni  $2p_{3/2}$  component located at 861.3 eV is related to a shake-up satellite of  $Ni^{3+}$  species.<sup>37,40</sup> The Co  $2p_{3/2}$  part of the Co 2p spectrum was fitted using three components as well. The Co  $2p_{3/2}$  component observed at 778.2 is attributed to  $Co^{3+}$  species, while the components located at 781.0, and 786.3 eV correspond to  $Co^{2+}$  main peak accompanied with its shake-up satellite, respectively.<sup>37,40</sup> For the S 2p high resolution XPS spectrum, the peak observed at 161.3 eV corresponding to S  $2p_{3/2}$  core level which is typical of metal sulfur bounds in the ternary metal sulfides<sup>41</sup> and consistent with nickel and cobalt sulfides.<sup>41</sup> The S 2p peak observed at 168.0 eV is attributed to surface sulfur with high oxide state, such as sulfates.



**Fig. 2** X-ray photoelectron spectroscopy (XPS) of  $CoNi_2S_4$  (a) survey scan and core-level spectra of (b) Co 2p, (c) Ni 2p and (d) S 2p.

The electrochemical performance of  $CoNi_2S_4$  micro-pseudocapacitor was tested in 2-electrode configuration in 1M KOH electrolyte. Unlike the EDLC behavior of rGO MSC where the charge is stored through the electrostatic accumulation of electrolytic ions, redox behavior from the  $CoNi_2S_4$  MSC is observed (see Fig. S3, ESI). As shown in Fig. 3a, the redox peaks appear at different scan rates, due to redox behavior of  $Co^{4+}/Co^{3+}/Co^{2+}$  and  $Ni^{3+}/Ni^{2+}$  couples, mediated by the hydroxyl ions ( $OH^-$ ) in the electrolyte. Since sulfur belongs to same group of oxygen,  $OH^-$  ions can induce electrochemical oxidation and reduction of  $CoNi_2S_4$  in alkaline medium similar to that of metal oxides/hydroxides. However, it is difficult to deconvolute the contributions of Ni and Co due to broad nature of redox peaks, most probably due to reversible formation of redox couples such as  $NiS/Ni(OH)$  and  $CoS/Co(OH)/CoSO$ . At a scan rate of 10 mV/s,  $CoNi_2S_4$  shows an areal cell capacitance of 11.6  $mF/cm^2$ , which is superior to binary metal oxide (areal cell capacitance of 1-5  $mF/cm^2$ ) and sulfide ( $VS_2$ ,  $MoS_2$ ;  $C_A = 4-8 mF/cm^2$ ) based micro-pseudocapacitors. It was found that the areal capacitance was gradually increasing from 1.7 to 11.6  $mF/cm^2$  (at a current density of 160  $\mu A/cm^2$ ) due to more loading of  $CoNi_2S_4$  when the deposition cycles were increased from 1 to 6 (see Fig. S4, ESI). Due to the planar configuration of the  $CoNi_2S_4$  interdigitated electrodes, CVs were recorded even at higher scan rates of 1-50 V/s as shown in Fig. 3c. Similarly, charge-discharge curves of  $CoNi_2S_4$  MSC at different current densities were recorded as shown in Fig. 3d. CD profiles are highly non-linear, clearly demonstrating the pseudocapacitive behavior the  $CoNi_2S_4$  electrodes. We have found that this micro-pseudocapacitor exhibits an areal cell capacitance of 11.6  $mF/cm^2$  (thickness of  $CoNi_2S_4/rGO$  is about 0.55  $\mu m$ ) which corresponds to a volumetric capacitance of 211  $F/cm^3$ . While pristine rGO based MSC shows a much lower areal capacitance of 0.3  $mF/cm^2$  with a volumetric capacitance of 40  $F/cm^3$ . Cycling stability of  $CoNi_2S_4$  MSC was tested by continuous charging/discharging at a current density of 320  $\mu A/cm^2$  which showed a capacitance retention of 80% after 5000 cycles with a Coulombic efficiency

above 95% (see Fig. S5, ESI). Further, solid state  $CoNi_2S_4$  MSC was fabricated by employing PVA/KOH gel electrolyte which exhibits an areal capacitance of 2.8  $mF/cm^2$  (see Fig. S6, ESI). Thus, enhanced values of areal and volumetric capacitance of  $CoNi_2S_4$  MSC is due to pseudocapacitive nature, unlike the EDLC behavior of carbon based MSCs. This volumetric capacitance is still higher than  $MoS_2$  MSC (178  $F/cm^3$ ). Thus, these ternary  $CoNi_2S_4$  with impressive redox contributions from the Ni and Co metals as well as facile ionic diffusion through the nanostructured electrodes give rise to high volumetric capacitance. Impedance spectrum for  $CoNi_2S_4$  micro-pseudocapacitor is shown in Fig. 3e. The presence of semi-circle in the high frequency region is due to charge-transfer resistance across the electrode/electrolyte interface with an equivalent series resistance (ESR) of 5  $\Omega$  (see inset of Fig. 3e). An optimized  $CoNi_2S_4$  micro-pseudocapacitor exhibits a maximum energy density of 18.7  $mWh/cm^3$  at a power density of 1163  $mW/cm^3$ . The energy density values are at least twice that of carbon,<sup>15</sup> and metal oxide based MSCs<sup>16,17</sup> ( $E = 1-10 mWh/cm^3$ ) fabricated in the literature. As shown in the Ragone plot in Fig. 3f,  $CoNi_2S_4$  MSC exhibit superior energy density over the binary sulfide based MSCs such as  $MoS_2$  ( $E = 6 mWh/cm^3$ )<sup>27</sup> and  $VS_2$  ( $E = 15 mWh/cm^3$ ) (see Table S1, ESI).<sup>28</sup> The  $CoNi_2S_4$  MSCs exhibit a maximum power density of 2327  $mW/cm^3$  even at an energy density of 14.2  $mWh/cm^3$ . This study opens up possibility of employing ternary sulfides as potential candidate electrode materials for on-chip energy storage with superior volumetric capacitance and energy density.



**Fig. 3** (a) Schematic showing the interdigitated electrodes of  $CoNi_2S_4$ . (b) and (c) CVs of  $CoNi_2S_4$  MSC in 1M KOH in 2-electrode configuration. (d) Charge-discharge curves at different current densities. (e) Impedance spectra of the device, inset shows high frequency region of the spectrum. (f) Ragone plot comparing the energy and power densities of  $CoNi_2S_4$  micro-pseudocapacitor with respect to  $MoS_2$  and  $VS_2$  micro-pseudocapacitors reported in the literature.

In summary, we have demonstrated the successful fabrication of micro-pseudocapacitors based on ternary nickel cobalt sulfides. This was achieved by employing single-step electrochemical co-deposition of nickel cobalt sulfide over transferred reduced graphene oxide (rGO) thin films followed by photo resist lift-off. The fabricated  $CoNi_2S_4$  micro-pseudocapacitors exhibit a maximum areal cell capacitance of 11.6  $mF/cm^2$  with a volumetric capacitance of 211  $F/cm^3$ . The maximum energy density of 18.7  $mWh/cm^3$  at a power density of 1163  $mW/cm^3$  was achieved, which is superior to the binary sulfide micro-supercapacitors reported in the literature. This study may open up an opportunity to fabricate various kinds of ternary oxides/sulfides based micro-pseudocapacitors.

Research reported in this publication was supported by King Abdullah University of Science and Technology (KAUST). Authors thank the Advanced Nanofabrication, Imaging and Characterization Laboratory at KAUST for their excellent support.

## Notes and references

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DOI: 10.1039/c000000x/

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